Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | IWATA ET AL. | Examiner | Art Unit | Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,064,248 A	05-2000	Seki, Nobusuke	327/296
	В	US-5,570,370 A	10-1996	Lin, Hung-Sheng	370/347
	С	US-6,763,060 B1	07-2004	Knapp, David J.	375/219
	D	US-6,643,787 B1	11-2003	Zerbe et al.	713/400
	Ε	US-5,493,571 A	02-1996	Engdahl et al.	370/514
	F	US-6,236,696 B1	05-2001	Aoki et al.	375/376
	G	US-6,466,634 B1	10-2002	O'Toole et al.	375/374
	Н	US-6,040,742 A	03-2000	Bailey et al.	331/2
	ı	US-6,229,362 B1	05-2001	Choi, Dong-myung	327/157
	7	US-5,670,913	09-1997	Garcia Palancar, Francisco Manuel	331/4
	к	US-5,889,828 A	03-1999	Miyashita et al.	375/374
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	2					
	0					
	ъ					
	Q					
	R					
	S					·
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	·
	\ \ \	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.